Table 1.1: Activities of ^{238}U , ^{232}Th and ^{40}K measured in relevant materials and following different techniques.

#	Material	Technique	Unit	^{238}U	^{232}Th	^{40}K	Ref.
	Shielding						
1	Pb, Cometa	GDMS	mBq/kg	0.37	0.073	<0.31	NEXT
2	Pb, Cometa		mBq/kg	<0.5	<0.5	<1	Cometa
3	Pb, Mifer	GDMS	mBq/kg	1.24	0.32		NEXT
4	Pb, Mifer, new provider	GDMS	mBq/kg	0.33	0.10	1.21	NEXT
5	Pb, Tecnibusa	GDMS	mBq/kg	0.73	0.14	0.91	NEXT
6	Pb, Tecnibusa	Ge (by LSC)	mBq/kg	<1.3 (e)	<0.9 (f)	<1.8	NEXT (+)
7	Cu, Luvata C10100	Ge (by UZ)	mBq/kg	<11.0*	<9.7*	<17.7*	NEXT
8	Cu, Luvata C10100 hot rolled	GDMS	mBq/kg	<0.012	<0.004	0.061	NEXT
9	Cu, Luvata C10100 cold rolled	GDMS	mBq/kg	<0.012	<0.004	0.091	NEXT
10	Cu, Electroformed	GDMS	mBq/kg	<0.062	<0.020		NEXT
11	Cu, ETP Sanmetal	GDMS	mBq/kg	<0.062	<0.020		NEXT
	Vessel						
12	Ti, Nironit, XENON	Ge	mBq/kg	0.93±0.24 (b)	0.22±0.10	0.90±0.30	[7]
13	Ti, LUX	Ge	mBq/kg	6.2±1.2, <0.19	<0.25	<0.9	[8]
14	Ti, LUX	GDMS	mBq/kg	52	2.5	<1.5	NEXT
15	Ti, LUX	Ge (by UZ)	mBq/kg	238±28	417±54	49±11	NEXT
16	Ti, LUX, after polishing	Ge (by UZ)	mBq/kg	<15*	4.2±1.4	<22*	NEXT
17	Ti, SMP	Ge (by LSC, GeOroel)	mBq/kg	<9.4 (e)	<9.4 (f)	<19	NEXT (+)
18	Ti, SMP	Ge (by LSC, GeTobazo)	mBq/kg	<6.3 (e)	<7.7 (f)	<9.3	NEXT (+)
19	Ti, Ti Metal Supply	Ge (by LSC)	mBq/kg	<0.30 (e)	3.2±0.3 (f)	<0.52	NEXT (+)
20	Stainless Steel, Pfeiffer 304L	Ge by UZ	mBq/kg	14.8±2.8 (a)	10.4±2.0 (a)	<16.6	NEXT
21	Stainless steel 316L, Elantic, UK, DRIFT	GDMS	mBq/kg	17.4±1.2	3.3±0.4	<9.3	[16]
22	Stainless steel 316L, block, Italy, DRIFT	GDMS	mBq/kg	<6.2	8.2±0.8	<9.9	[16]
23	Stainless steel 316L, SNOlab	Ge	mBq/kg	0.63±0.15 (b)	0.62±0.15	<0.97	[6]
24	Stainless steel 316Ti, Nironit, XENON	Ge	mBq/kg	<1.9 (b)	<1.0 (d)	10±4	[4]
25	Stainless steel Austenitic 1.4571, GERDA	Ge	mBq/kg	<0.24 (b)	<0.11 (d)	<0.93	[5]
26	Stainless steel TIG, SNOlab	Ge	mBq/kg	1.01±0.71 (b)	2.8±0.8	<1.45	[6]
27	Inconel 718	Ge (by LSC)	mBq/kg	<5.6 (e)	<4.6 (f)	<11	NEXT (+)
28	Inconel 625	Ge (by LSC)	mBq/kg	<1.8 (e)	<2.0 (f)	<2.6	NEXT (+)

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#	Material	Technique	Unit	^{238}U	^{232}Th	^{40}K	Ref.
29	PCTFE, Daikin Neoflon, EXO	Ge	mBq/kg	5.6±1.2	<2.3	<30	[9]
30	Viton, O-ring seal, Johannsen AG, EXO	Ge	mBq/kg	868±87	130	2170±226	[9]
	HV and EL components						
31	Peek, Sanmetal	Ge (by UZ)	mBq/kg	36.3±4.3	11.7±2.2	8.3±3.0	NEXT
32	Peek	Ge	mBq/kg	<70 (b)	<50 (d)	<260	[10]
33	SM5D, 700MΩ resistors, Finechem, XENON	Ge	mBq/pc	0.027±0.003 (b)	0.014±0.003 (d)	0.19±0.03	[4]
34	SMD resistors, Finechem	Ge (by UZ)	mBq/pc	0.022±0.007 (e)	<0.016* (f)	0.17±0.07	NEXT
35	SMD resistors, Farnell	Ge (by UZ)	mBq/pc	0.15±0.04 (e)	0.28±0.06 (f)	0.19±0.08	NEXT
36	Polyethylene, EDELWEISS	Ge	mBq/kg	16±10 (e)	<6 (f)	70±50	[16]
37	Polyethylene, XENON	Ge	mBq/kg	0.23±0.05 (b)	<0.14 (d)	0.7±0.4	[4]
38	Polyethylene insulator, EXO	NAA	mBq/kg	<2.9	<0.57	1.46±0.22	[9]
39	Tetratex, ArDM	ICPMS	mBq/kg	12.4±3.7	<1.6	<16	[11]
40	TPB, Sigma-Aldrich, SNOlab	Ge	mBq/kg	1.63±1.01 (b)	0.47±1.11	8.22±12.03	[6]
41	TPB, American Chemicals, SNOlab	Ge	mBq/kg	<4.33 (b)	<1.69	<36.29	[6]
42	Teflon, Du Pont TE-6472, EXO	NAA	mBq/kg	<0.0096	<0.0011	0.0558±0.0062	[9]
43	PTFE, Dyneon TF 1620, GERDA	Ge	mBq/kg	0.025±0.009 (b)	0.031±0.014 (d)	0.60±0.11	[12]
	Detector components: energy plane						
44	PMT, Hamamatsu R8520, XENON	Ge	mBq/PMT	0.19±0.01 (b)	0.20±0.02(d)	9.9±0.4	[4]
45	PMT base, Hamamatsu R8520, XENON	Ge	mBq/base	0.16±0.02 (b)	0.07±0.02 (d)	<0.16	[4]
46	PMT, Hamamatsu R11410MOD, XENON	Ge	mBq/PMT	<2.4 (b)	<2.6 (d)	13±4	[4]
47	PMT, Hamamatsu R11410MOD, LUX		mBq/PMT	<0.4	<0.3	<8.3	[15]
48	PMT, Hamamatsu R11410MOD		mBq/PMT	3.3	2.3	5.7	Hamamatsu
49	Sapphire, Czochralsky Type, ROSEBUD	Ge	mBq/kg	<5 (e)	<5(f)	<30	[16]
50	Sapphire, Verneuil Type, ROSEBUD	Ge	mBq/kg	<3 (e)	<3(f)	<12	[16]
51	Sapphire window, EXO	NAA	mBq/kg	<0.31	0.123±0.029	<0.20	[9]
52	Quartz, Heraeus 2, EXO	NAA	mBq/kg	0.068±0.027	0.027±0.005	0.062±0.016	[9]
	Detector components: tracking plane						
53	Cuflon, circuit board, EDELWEISS	Ge	mBq/kg	<23 (e)	<30 (f)	400±200	[16]
54	Cuflon, Crane Polyflon, GERDA	Ge	mBq/kg	<0.85 (b)	<1.9 (d)	±15	[12]
55	Cuflon	Ge	mBq/kg	<0.84 (b)	<1.9	48±15	[18]
56	Cuflon	ICPMS	mBq/kg	$0.36^{+0.07}_{-0.04}$	$0.28^{+0.04}_{-0.03}$	6^{+9}_{-2}	[18]
57	ARJOPROX, ARLON	Ge	Bq/kg	<0.044 (e)	<0.065 (f)	0.3±0.2	[16]
58	ARAMID paper, CIMULEC	Ge	Bq/kg	<0.06 (e)	0.04±0.03 (f)	0.15±0.14	[16]
59	Kapton, AXON	Ge	Bq/kg	0.07±0.03 (e)		0.3±0.2	[16]
60	Kapton+Cu, KAPPA Industrie	Ge	Bq/kg	0.014±0.012 (e)	0.013±0.012 (f)	<0.09	[16]
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#	Material	Technique	Unit	^{238}U	^{232}Th	^{40}K	Ref.
61	Kapton+Cu, SOGGEG (g)	Ge	Bq/kg	<0.08 (e)	0.05±0.04 (f)	<0.9	[16]
62	Kapton+Cu, CIRE (g)	Ge	Bq/kg	0.09±0.05 (e)	<0.08 (f)	0.7±0.4	[16]
63	Kapton+Cu, CIRE (g)	Ge	Bq/kg	0.28±0.26 (e)	0.3±0.2 (f)	<2.1	[16]
64	Kapton+Cu ATLANTEK (g)	Ge	Bq/kg	<0.06 (e)	<0.02 (f)	0.4±0.2	[16]
65	Polyamide+Cu VISHAY	Ge	Bq/kg	9.1±0.2 (e)	3.3±0.2 (f)	7.0±0.7	[16]
66	FR4 PCB	Ge (by UZ)	Bq/kg	0.4	0.24	1.5	
67	Kapton-copper foil	Ge (by UZ)	mBq/cm^2	<0.011	<0.0046*	<0.0077*	[19]
68	Kapton-copper PCB, LabCircuits	Ge (by UZ)	mBq/cm^2	<0.014* (e)	<0.003* (f)	<0.040*	
69	EPO-TEK 301-2FL, Epoxy Tech.	Ge	mBq/kg	9±3 (b)	<60 (d)	<25	[20]
70	EPO-TEK H20E, silver, Epoxy Tech.	Ge	mBq/kg	<25 (e)	<40 (f)	600±400	[16]
71	EPO-TEK 417F, silver, Epoxy Tech.	Ge	mBq/kg	68±11 (b)	<131 (d)	<65	[20]
72	Tra-Con Tra-Duct 2902 silver epoxy, Ellsworth	ICPMS	mBq/kg	0.98±0.05	0.045±0.004		[21]
73	FFC/FCP connector, Molex	Ge	mBq/unit	3.0±0.2 (e)	1.8±0.1 (f)	3.5±0.5	[16]
74	Tantalum capacitor, AVX	Ge	Bq/kg	0.32±0.05 (e)	0.41±0.05 (f)	0.3±0.2	[16]

(a) Average on different isotopes
(b) Activity of ^{226}Ra
(c) Two values for early/late part of chain
(d) Activity of ^{228}Th
(e) Activity from ^{214}Bi
(f) Activity from ^{208}Tl
(g) Special fabrication
(*) Level obtained from the minimum detectable activity of the detector (MDA)
(+) Preliminary result.

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